

矽光子異質整合封裝與測試之技術趨勢與挑戰

Technology Trends and Challenges in Packaging and Testing for SiPh Heterogeneous Integration

LIGHTMATTER

Jesse Wang
Director, Supply Chain Operations
2026/05/28



ZM
\$850M RAISED

Fidelity
Google Ventures
Sequoia
Spark Capital

Viking
T. Rowe Price
Matrix Partners
SIP Capital

MIT
Stanford



Mountain View (HQ)



Boston



Hsinchu, Taiwan



Toronto

320
EMPLOYEES



Nicholas Harris, PhD
Founder, CEO



Darius Bunandar, PhD
Founder, Chief Scientist



Thomas Graham
Founder, Head of ML



Simona Jankowski
CFO



Ritesh Jain
SVP, Engineering & Ops



Bob Turner
SVP, Sales & Solution Arch



Roy Kim
VP, Product



Sujatha Wagle
VP, Supply Chain Ops



Beth Keil
SVP, People



Boon Tan
VP, Product Engineering



Colin Sturt
General Counsel



Kaushik Patel, PhD
VP, Photonics & SI Eng



Steve Klingler
VP, Ecosystem & Alliances



Praveen Kulkarni
VP, Sales



Kurt von Hausen
VP, Cloud Services Sales

405
PATENTS



Granted & Pending

CO-PACKAGED OPTICS INDUSTRY ECOSYSTEM

yw@warren@gmail.com 2026-06-22 from IP: 125.228.95.152



PIC design



LIGHTMATTER celestial AI

SOI wafer & Epi-wafer



Light Source (Device)



ELSFP (Module)



ASIC & xPUs design



Foundries



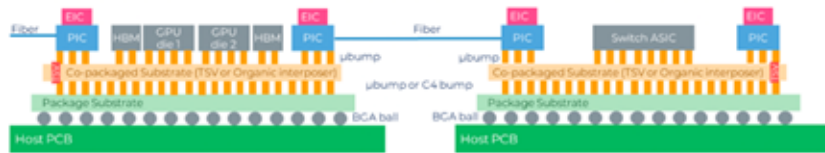
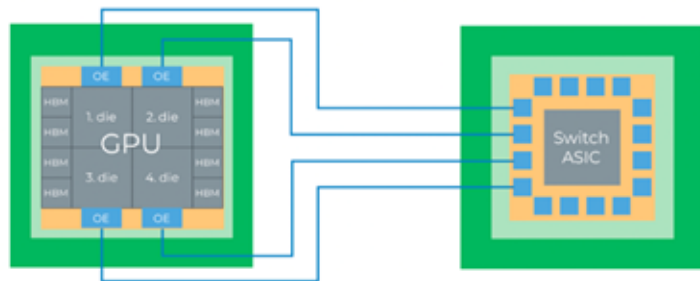
Packaging / System assembling / Testing



CPO Equipment (AI server or switch)



End customers (CPO users)



EIC & DSPs, Retimers, SerDes, PHY



Connectors

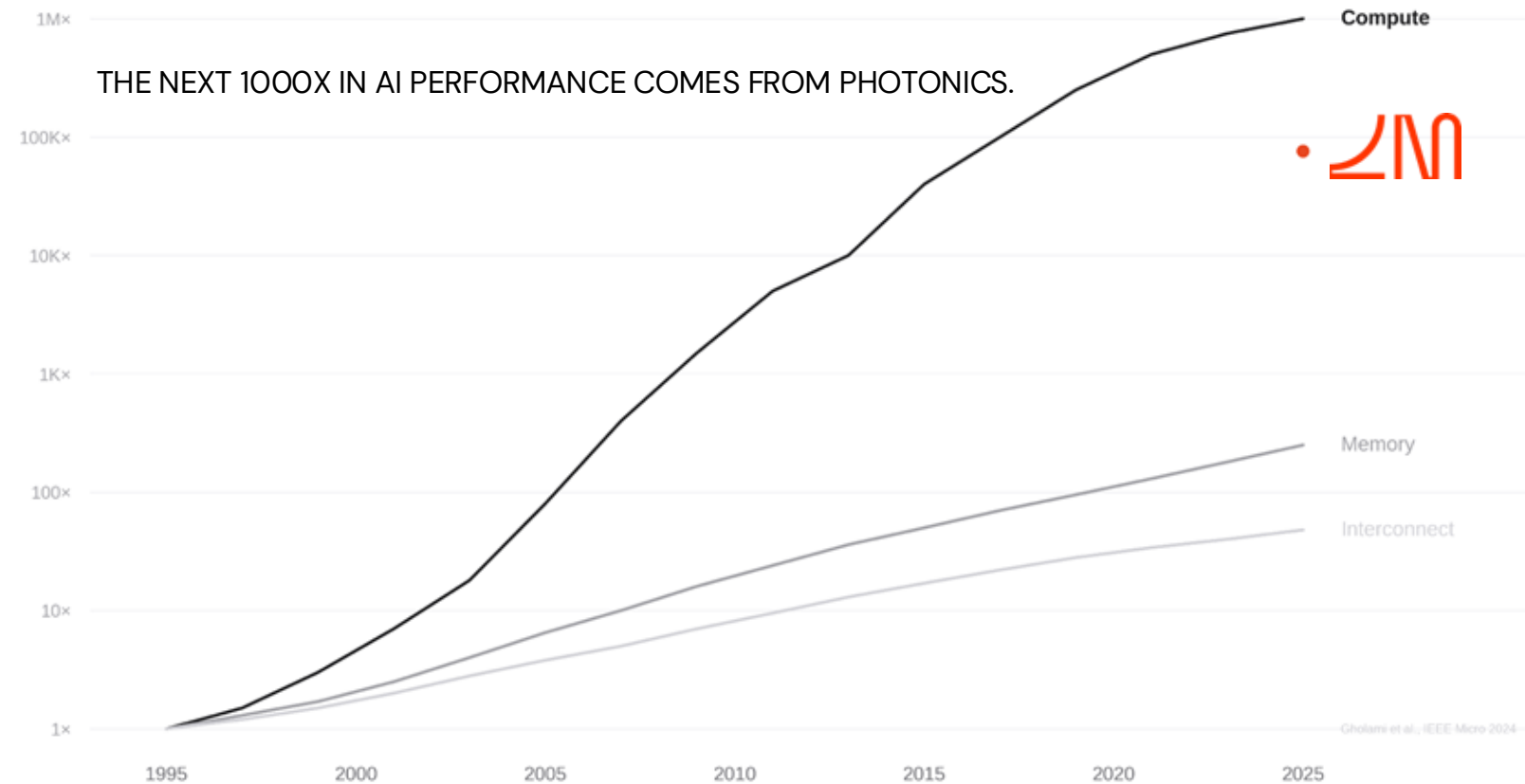


Fibers



*non-exhaustive list Powering the Next Wave of Data Infrastructure with Co-Packaged Optics | SPIE Industry Event



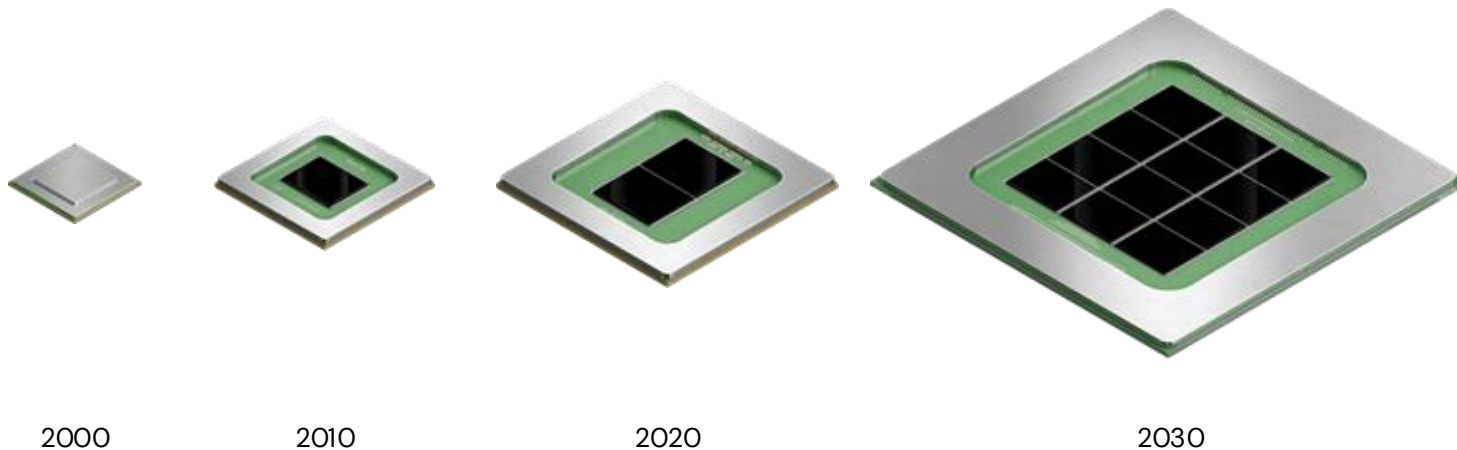


The last 1,000x in AI performance was all about compute.

The next 1000x is all about **interconnect**.

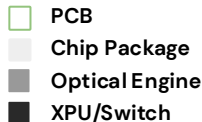
CHIPS ARE GETTING BIGGER

I/O at the shoreline is not enough
3D-stacked photonics is the future

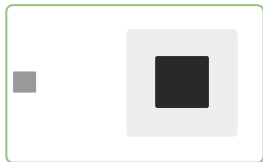


The Promise of Silicon Photonics

Moving Closer to the Chip

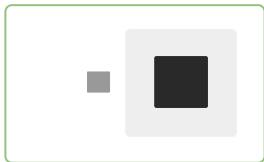


2025



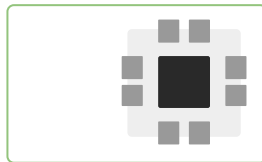
GEN 1
Pluggables

2027



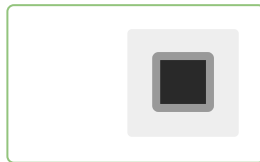
GEN 2
NPO/OBO/XPO

2028



GEN 3
2D CPO

2029+



GEN 4
3D CPO/Interposer

Power
Efficiency

17-20
pJ/bit

8-15
pJ/bit

6-10
pJ/bit

1-3
pJ/bit

Bandwidth

1x
Speedup

2x
Speedup

8x
Speedup

100x
Speedup

- Pre-packaged OE (PIC+EIC)
- LR SerDes, Re-timer

- I/O chiplet (PIC+EIC)
- In-package, XSR SerDes

- 3D stacked PIC/EIC chiplet
- Standard pkg, UCle
- Advanced package, OCS

From NPO to 3D Interposers, Lightmatter has the 10 year roadmap for photonics in validation racks today

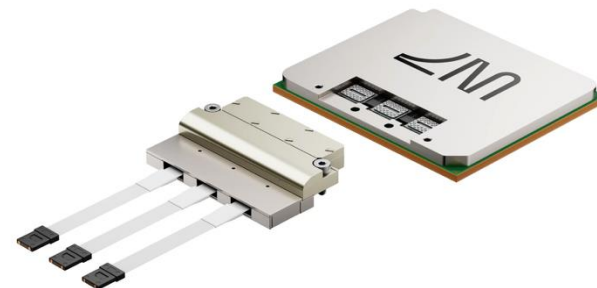
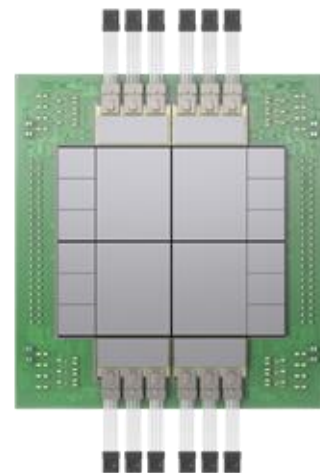
Advantages of CPO Technology

Reliability:

- Fewer Failure Points: It reduces discrete components and physical connectors, common points of failure in massive clusters.
- Thermal Stability: The integrated nature allows for unified cooling strategies, provide more stable temperature management for sensitive optical components.

Serviceability:

- Encouraging results with Pluggable Laser Sources (Remote Laser Module)
- Detachable Fiber Attach Unit (dFAU)
- Detachable Optical Engine



Why Hyperscalers Are Focusing on CPO Now



Power per bit must
drop sharply



Cabling complexity
must collapse



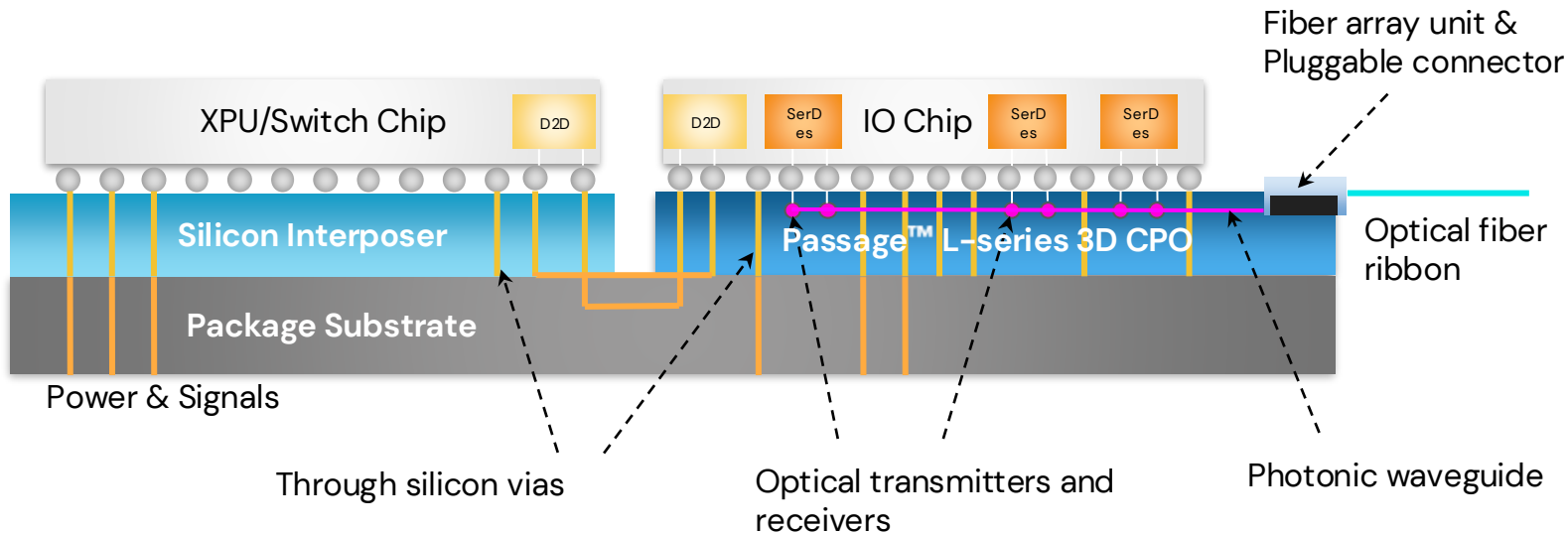
Reliability must
improve at million-
link scale



System density
must rise without
copper/thermal
overload

CPO Solves All 4 Simultaneously:
Up to 1K XPUs at $\frac{1}{4}$ the power, 4X the Bandwidth, 5X Reliability

3D Stacking Needs Compact Optical Devices



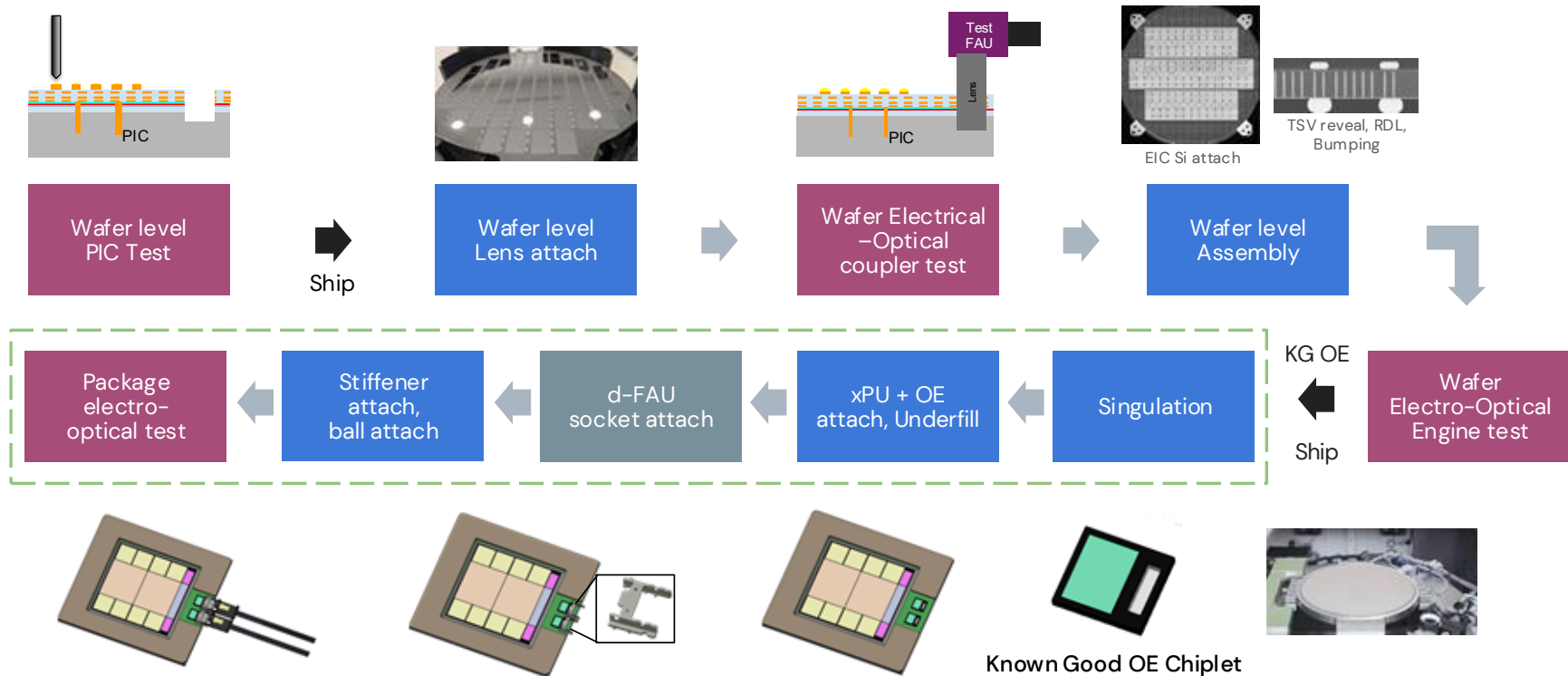
Standard processes today

Bump pitch: $\sim 120\ \mu\text{m}$

Bump size: $\sim 80\ \mu\text{m}$

Area for a transmitter/receiver: $0.015\ \text{mm}^2$

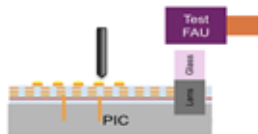
Integrated Assembly and Test Process Flow



Test Point Flow

TP1

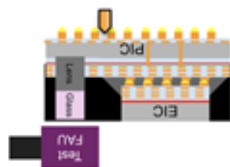
PIC Wafer Level
Test (vertical coupled)



EE, OE, OO main
circuit

TP2

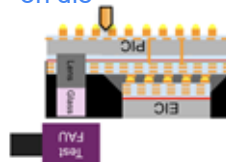
Bonded OE (PIC+
EIC stack) on wafer



EE, OO Main circuit,
OE main circuit

TP3

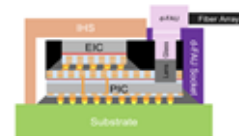
Singulated OE
(PIC+ EIC stack)
on die



EE, OO Main circuit,
OE Main circuit

TP4

Packaged OE/SLT



OE main circuit,
High speed

Focus Areas for CPO development



KGOE Integration

Delivering Known Good Optical Engines (KGOE) for seamless mainstream packaging integration.



Cost Optimization

Economic solutions for Package, Assembly, and Test phases in high-volume flows.



Fiber Attach

Driving breakthrough innovations in Fiber Attach Technology and detachable interfaces.



HVM Equipment

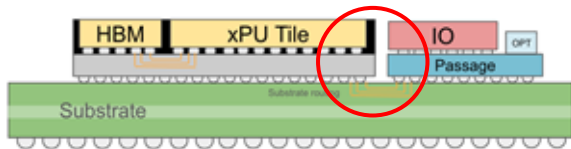
Deploying HVM-friendly optical attach equipment and low-cost metrology systems.



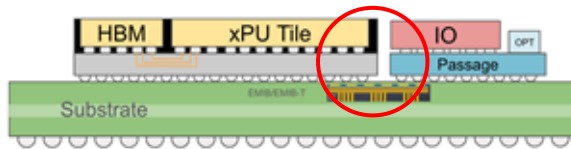
Materials & FAU

Utilizing HVM-friendly materials and standardized FAU solutions for scalability.

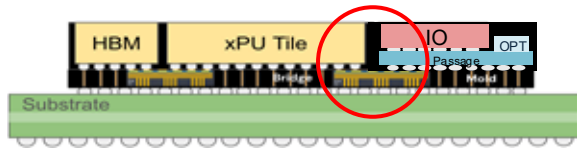
Deliver Known Good Optical Engines



xPU to OE link: routing on organic substrate



xPU to OE link: routing on Silicon Bridge →
EMIB Package Technology



xPU to OE link: routing on Silicon Bridge or Si Interposer
→ CoWoS_L/S Package Technology

Deliver Cost Effective Solutions

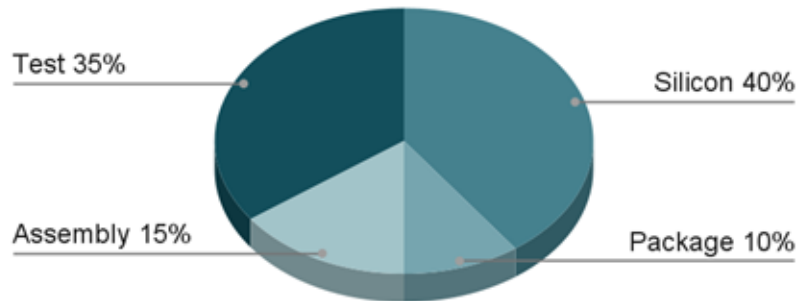
Backend Costs (PAT) are High. Driven by

- Assembly yield concerns due to fiber attach
- Higher test times
- Lack of standardization

Key Vectors:

- Design product with DFT/DFM upfront
- Drive Innovation in fiber attach
- Equipment & material development to improve throughput in assembly and test

SiPho Cost Breakdown



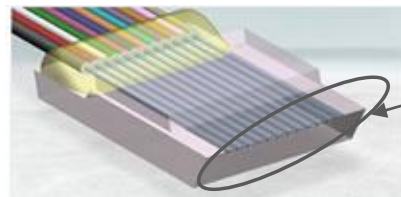
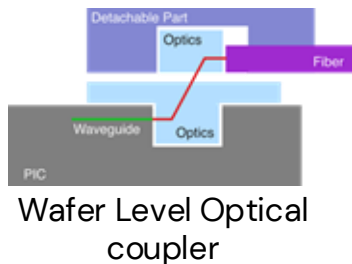
Note: Graph shown for demonstration purposes only

Deliver Scalable Fiber Attach Solutions

Key Performance Indicators
for HVM



High Yield	✓
Meet Product Performance	✓
High Throughput (UPH, units per hr)	✓
Known Good OE	✓
Scalable across package arch	✓
Serviceability	✓



FAU facet with PM fiber



FAU cost

- FAU is one of the main BOM cost
 - manual manufacturing process
- Automated PM fiber orientation
- Automated fiber insertion into MT ferrule
- Standardization of connector spec

Deliver Scalable Solutions for HVM

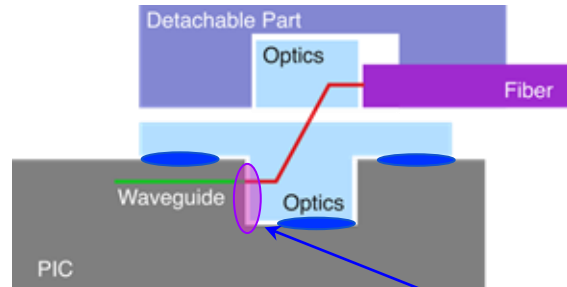


Equipment

- Transition to automated alignment in seconds, not minutes
- Parallel processing: handling, alignment, dispense and UV cure
- Re-configurable to support multiple products

Materials

- Single epoxy for the entire OE
- Reflow compatible materials
- Fast UV cure (<5 sec) instead of 30 sec to minutes
- Low Tg (conforms with warpage change)



IME + Mechanical
Epoxies

LM Methodology & Partnership for HVM Readiness

Design/Architecture

- SI/PI
- Substrate Design
- Design for manufacturing /Reliability
- Thermal analysis
- Mechanical Design /Analysis
- Optical Analysis

Assembly/Test

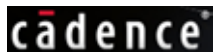
- 2D and 3D Heterogeneous Integration & process dev.
- Wafer Electrical Sort and Optical Characterization
- Wafer and component test points through the process flow

Yield/Data Management

- Database with lot/unit level traceability
- Best known methods development to manage yield analysis
- Failure analysis and corrective action including binning strategies

Reliability/Validation

- Electrical and Compliance Tests – ESD, Latch Up, EMI/EMC
- Package/Environmental – TC, UHAST, HTS, S/V, Fiber Integrity
- Operational – HTOL
- Failure rate and Lifetime prediction

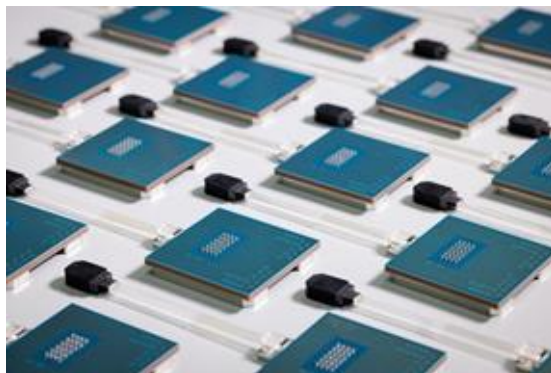


Lightmatter's Leadership in Photonics



10-year roadmap in silicon today

M1000 3D photonic superchip with record-breaking 114Tbps bandwidth



Leading bandwidth density

**World's first 16-wavelength DWDM link:
800G/fiber bidirectional &
1.6T/fiber unidirectional**



Rackscale quality and reliability

Validation data center with hundreds of photonic interconnects

3D Photonics Ecosystem

Custom ASIC
Partners

GUC
and others

Passage™ SerDes
EIC Partners

cadence
Qualcomm
SYNOPSYS

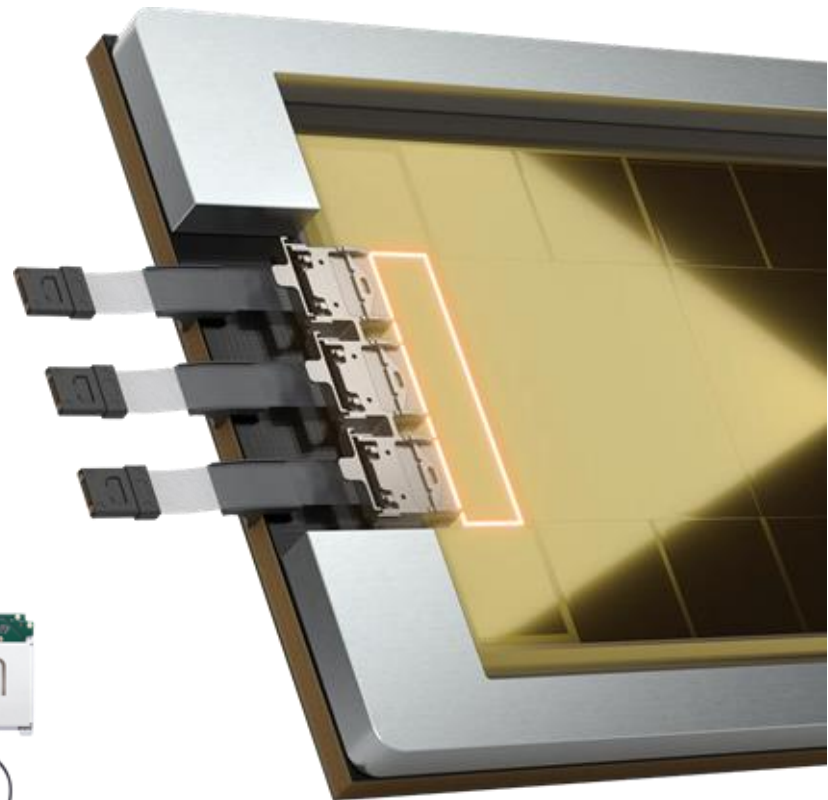
LIGHTMATTER
Passage™ PIC

tsmc
Tower Semiconductor

Detachable
Fiber Array Unit

SENKO 波普威科技
TwinstarTech OPTIC CORPORATION

Guide® VLSP™
Light Engine



THANK YOU!

